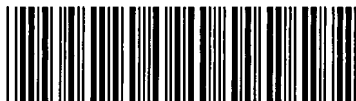


**Search Notes**

Application/Control No.

10/526,400

Examiner

Nam Huynh

Applicant(s)/Patent under  
Reexamination

POYKKO ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
See	Previous	12/6/2006	NTH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
A further evaluation of previously cited references was conducted	5/29/2007	NTH